nanoFAB Online Sample Submission Procedure

Feb. 22nd, 2019

1. Log onto LMACS
2. Click ***"Requests"*** button

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Laboratory Management & Access Control System (LMACS)

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Submit a New Request

Manage Requests

Title

XPS analysis.

Select Project

Nanofab.Process_Development

Select Type

Sample

Select Equipment (optional)

XPS Imaging Spectrometer (Kratos AXIS Ultra)

Summary

I would like to submit 4 samples for XPS analysis.

Return any samples

You can attach additional information (files/steps..) in the next step

Create Request

3. Fill in general information
    - Select Type – ***"Sample"***
    - ***"Return any Samples"*** - Indicate whether you like samples to be returned or not upon completion of analysis.
    - Click ***"Create Request"*** button

4. Click ***"Edit Request"*** to add detailed description of samples and analysis.

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Submit a New Request

Manage Requests

That's it!

You've completed the minimum information required to get started. If you would like to add additional information to your request, you can click the "Edit Request" button. You can also view / edit your other pending requests from the list below.

Edit Request

Pending Requests

14 results

Title	Submitted	Modified	Status
XPS analysis. Sample	Mar 5th	Mar 5th	Submitted

5. Edit sample details in ***"Add item(s)"*** session:

- One sample per item
- Sample name in Label
- Select ***"Sample"*** type
- Add sample information and analysis details in ***"description"***
- Click *"**Add Item**"*

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Laboratory Management & Access Control System (LMACS)

Manage | Facility | Equipment | Photomasks | Requests | Peng Li | Admin | ?

XPS analysis.

Request ID: 2172

Submitted by: Peng Li

Item Details 0

Empty
No items have been added to this request yet.

Comments 0

add your comment...

Add Comment | private

History 2

Mar 5,2017 10:04pm	Peng Li changed Assigned To From: nobody To: Peng Li
Mar 5,2017 10:04pm	Peng Li initially created this request.

Summary Submitted

Add Item(s)

Label
SiO2 nanoparticles (####)

Type
Sample

Select Equipment (if applicable)
XPS Imaging Spectrometer (Kratos AXIS Ultra)

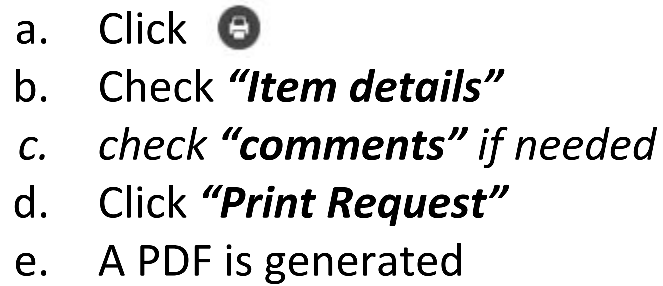
Due Date
optional due date

Assign To
Assign Users

Description
Survey scan and high resolution scan of Si and O.

Add Item

6. Print your request after completing editing sample details.



a. Click
b. Check ***"Item details"***
c. *check **"comments"** if needed*
d. Click ***"Print Request"***
e. A PDF is generated

7. Print a hard copy, attach it to your samples and submit them to the nanoFAB Characterization Lab (**ECERF W1-040**)

Please include your request ID and Item ID in any related communication with nanoFAB staff members.

nanoFAB Request Detail Printed : Mar 5, 2017

XPS analysis.	**Request ID: 2172**
Project: Nanofab.Process_Development	Submitted By: Peng Li
Status: Submitted	Submitted Date: Mar 5, 2017
Type: Sample	Last Modified: Mar 5, 2017
Priority:	Due Date:
Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Assigned To: Peng Li

Description: I would like to submit 4 samples for XPS analysis.

Items (4)

ID: 2172-1686: SiO2 nanoparticles (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017
Survey scan and high resolution scan of Si and O.		

ID: 2172-1687: TiO2 nanoparticles (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017
Survey scan and high resolution scan of Ti and O.		

ID: 2172-1688: TiO2 thin film (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017
Survey scan and high resolution scan of Ti and O and depth profile measurement of Ti and O. Sample: 10nm TiO2 film on Si substrate.		

ID: 2172-1689: TiO2 thin film (####) (Sample)

Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017
Survey scan and high resolution scan of Ti and O and depth profile measurement of Ti and O. Sample: 20nm TiO2 film on Si substrate.		

Any samples submitted will be discarded. If you wish to have your samples returned, contact the nanoFAB

8. Files and Comments:

- Results will be uploaded in the ***"Files"*** session after completion of analysis.
- Users can also upload related documents here
- Communication is best through ***"Comments"*** session.

XPS analysis.

Request ID: 2172

Submitted by: Peng Li

Include: Comments, Files, Bookings, Item Details — Print Request

Item Details (4)

Drag to reorder

Label	Type	Description	Assigned	Resource
1 SiO2 nanoparticles (####) ID:2172-1686	Sample	Survey scan and high resolution scan of Si and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) Edit — Submitted
2 TiO2 nanoparticles (####) ID:2172-1687	Sample	Survey scan and high resolution scan of Ti and O.	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) Edit — Submitted
3 TiO2 thin film (####) ID:2172-1688	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) Edit — Submitted
4 TiO2 thin film (####) ID:2172-1689	Sample	Survey scan and high resolution scan of Ti and O a...	Peng Li	XPS Imaging Spectrometer (Kratos AXIS Ultra) Edit — Submitted

Summary — Submitted

Add Item(s)

Label: TiO2 thin film (####)

Type: Sample

Select Equipment (if applicable): XPS Imaging Spectrometer (Kratos AXIS Ultra)

Due Date: optional due date

Assign To: Assign Users

Description: and O. Sample: 20nm TiO2 film on Si substrate.

Add Item

Comments (0)

add your comment...

You must have something to say

Files (0)

Add File(s)

Drag & Drop Files

9. Sample Pickup

- Returning samples are to be picked up at the Characterization Lab **(ECERF W1-040)**.

10. Data processing and software training

- Analysis softwares are available at the common computers in **ECERF W1-028**
- Should you require software training (CasaXPS, JADE-XRD, Oxford EDX, JEOL EDX, SIMS), please submit a training request on LMACS - select tool "**Characterization software.**".

Characterization staff members:

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